

# MAPAN-Journal of Metrology Society of India

## CALL FOR PAPERS FOR SPECIAL ISSUES ON

The *MAPAN-Journal of Metrology Society of India*, a leading SCI indexed quarterly publication, exclusively devoted to Metrology (Scientific, Industrial or Legal), is being published by Metrology Society of India in collaboration with well known international publication house i.e. Springer, Germany; National Physical Laboratory (NPL) and Council of Scientific and Industrial Research (CSIR), New Delhi, India. In the past, several theme based special issues have been published in the journal on various aspects of metrology by eminent metrologists as *Guest Editors*. In continuation of such efforts, the journal has decided to publish two more special issues during the year 2012 on the following topics;

### i) *Advanced Frequency Standards* (Scheduled for March, 2012)

#### *Guest Editors:*

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### ii) *Acoustics, Ultrasound and Vibration Metrology for Safety and Health* (Scheduled for December, 2012)

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